

## Substrate patterning for liquid crystal alignment by optical interference

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(Received 2 January 2006; accepted 22 April 2006; published online 13 June 2006)

Inhomogeneous liquid crystal (LC) alignment surfaces comprising a succession of microdomains favoring different LC alignment directions have been demonstrated for a number of optoelectronic applications. However, the prevalent method used to fabricate these surfaces is time consuming and produce functional areas that are too small for practical use. Here, we demonstrate a simple method based on photopatterning of an azodye layer with an interference pattern produced by intercepting two coherent UV beams. This method can produce alignment patterns within seconds with a practical size of  $\sim(0.5 \text{ cm})^2$ . © 2006 American Institute of Physics. [DOI: 10.1063/1.2209713]

There has been an enormous interest within the liquid crystal (LC) community to fabricate patterned LC alignment surfaces for their promises in numerous applications,<sup>1</sup> such as wide-viewing-angle display,<sup>2,3</sup> projection display,<sup>4</sup> optical grating,<sup>1,4-9</sup> bistable<sup>10</sup> and tristable<sup>11</sup> displays, no-bias bend-play display,<sup>12</sup> and alignment surfaces with tunable LC pretilt angle,<sup>13</sup> etc., as well as the corresponding ordering phenomena.<sup>14-17</sup> This has led to a proliferation of methods for making these surfaces, including atomic force microscopic (AFM) nanolithography,<sup>8,10-13,15-17</sup> polarization holography,<sup>1,9</sup> lithographic patterning of a photosensitive layer,<sup>2,18-21</sup> double rubbing,<sup>4</sup> microrubbing,<sup>4,5,7</sup> laser writing,<sup>22</sup> use of homeotropic and homogeneous polyimide mixtures,<sup>12</sup> etc. Among these methods, only the first method has been demonstrated for making patterns with inhomogeneous in-planned alignment and periods of  $\sim 1 \mu\text{m}$ , which is desirable in some of the aforementioned technologies.<sup>10-13</sup>

In this letter, we describe a method for making micro-patterned surfaces for LC alignment, in which an azodye film is exposed twice to an interference fringe pattern produced by intercepting two UV laser beams sequentially  $p$  and  $s$  polarized, with the interference pattern laterally shifted by a half period between the exposures. It produces patterns composed of alternating  $x$ - and  $y$ -alignment stripes (where  $x$  and  $y$  are the projections of the UV polarization direction  $\mathbf{P}$  in the film during  $p$  and  $s$  polarization, respectively). This method is simple, fast, and allows easy control of the pattern period and LC azimuthal alignment direction.

The azodye used is the so-called SD-1 supplied by Dainippon Ink and Chemicals, Japan. The procedure of preparing the SD-1 films on indium tin oxide (ITO) glass can be found in Ref. 23. The SD-1 molecules possess an UV absorption peak at 327 nm.<sup>23</sup> Illumination with linearly polarized UV near this wavelength produces LC alignment perpendicular to the polarization.<sup>24</sup>

Figure 1 shows our setup. The He-Cd laser produces cw UV beam with wavelength  $\lambda=325 \text{ nm}$  and linear polariza-

tion,  $\mathbf{P} \parallel \mathbf{y}$ . We first rotate  $\mathbf{P}$  by  $90^\circ$  by turning the optic axis of  $\lambda/2$ -plate-1 to  $45^\circ$  with respect to  $\mathbf{y}$ . Then the beam is split into two with one afterward passing through  $\lambda/2$ -plate-2, which has the optic axis along  $\mathbf{y}$ . Then the two ( $p$  polarized) beams are recombined to produce an interference fringe pattern to which the SD-1 film is exposed for time  $\tau_1$ . Then  $\mathbf{P}$  is returned to  $\mathbf{y}$  by adjusting  $\lambda/2$ -plate-1, causing the intercepting beams to be  $s$  polarized. With  $\mathbf{P} \parallel \mathbf{y}$ , the beam passing through  $\lambda/2$ -plate-2 acquires a phase change of  $\pi$  with respect to the first exposure thereby the fringes are shifted laterally by a half period. The SD-1 film is then exposed to this pattern for time  $\tau_2$ . The pattern period  $p$  is adjustable through the angle  $2\sigma$  ( $p=\lambda/2 \sin \sigma$ ). Lenses 1 and 2 expand the UV beam from  $\sim 1.5$  to  $\sim 5 \text{ mm}$ .

Figure 2 shows the optical images of LC cells constructed from four hence patterned SD-1 films (constituting the bottom wall; the upper wall is ITO glass coated with polyimide uniformly rubbed along  $\mathbf{y}$ ; the cell gap is  $25 \mu\text{m}$ ), placed between crossed polarizers. The LC is nematic 4'- $n$ -pentyl-4-cyanobiphenyl (5CB). Table I lists the exposure conditions used for the  $p=2, 1.67, \text{ and } 0.78 \mu\text{m}$  patterns. In Fig. 2, except for the  $p=0.78 \mu\text{m}$  cell, periodic dark and bright fringes are clearly visible, suggesting the LC alignment to be alternating between  $x$  and  $y$ . When the analyzer is rotated to the  $\phi=-45^\circ$  azimuthal direction, all four cells appear dark, confirming the bulk LC alignment to be uniform along  $\phi=+45^\circ$ . The uniform appearance of the  $p=0.78 \mu\text{m}$  cell can be due to the fringes being too narrow

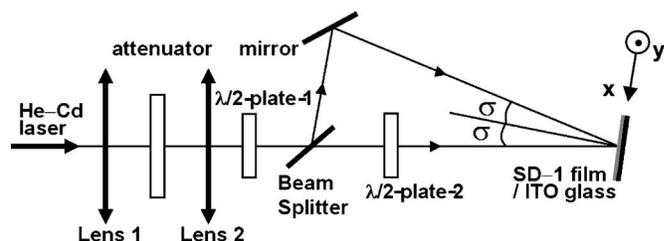


FIG. 1. Setup used to produce the inhomogeneous LC alignment pattern on the SD-1 films. The components labeled  $\lambda/2$ -plate- $i$  ( $i=1,2$ ) are half-wave plates.

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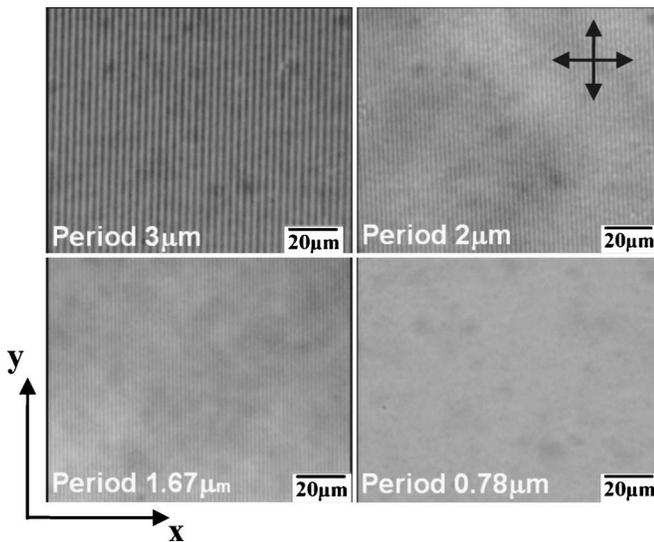


FIG. 2. Optical images of four representative LC cells constructed from SD-1 films patterned with different periods as shown. The double-sided arrows indicate the polarizer and analyzer directions used in taking the pictures.

to be resolved optically or the LC director field essentially uniform along  $\phi = +45^\circ$ .<sup>15</sup>

We measure the effective azimuthal surface energy  $W_{\phi, \text{eff}}$  for bulk LC alignment along  $\phi = +45^\circ$  of the  $p=2$ , 1.67, and 0.78  $\mu\text{m}$  patterns as detailed in Ref. 25. For comparison, we measure the azimuthal surface energy  $W_\phi$  of similarly exposed SD-1 films, but the UV polarization was held  $\parallel y$  in both exposures. The results show that  $W_{\phi, \text{eff}}/W_\phi$  is between 0.05 and 0.2 (Table I), which is consistent with the former result obtained from checkerboard-textured surfaces.<sup>15</sup>

Figure 3 displays plots of the average LC azimuthal alignment  $\phi$  vs  $\tau_2$  (solid circles) for the  $p=0.78$ , 1.67, and 2  $\mu\text{m}$  patterns subject to the otherwise same exposure conditions given in Table I. As seen,  $\phi$  (measured from  $x$ ) decreases monotonically from  $90^\circ$  to  $0^\circ$  as  $\tau_2$  increases. It means that the ratio of the summed area of the  $x$  alignment domain  $A_x$  to the total area of the film  $A_{\text{tot}}$  progressively increased from 0 to 1. According to a previous result,<sup>24</sup> the orientation of the azodye molecules in a freshly prepared SD-1 film is random. The first exposure produces azodye alignment along  $y$  with varying degrees [i.e.,  $\langle P_2(\theta) \rangle$  is varying; here,  $\langle \dots \rangle$  denotes ensemble averaging,  $P(\theta) = (1/2) \times (3 \cos^2 \theta - 1)$ , and  $\theta$  is the orientation of the azodye molecule with respect to  $\mathbf{P}$ ] according to the intensity profile of the fringes. The second exposure causes progressive rotation of the azodye molecules away from the alignment along  $y$ .

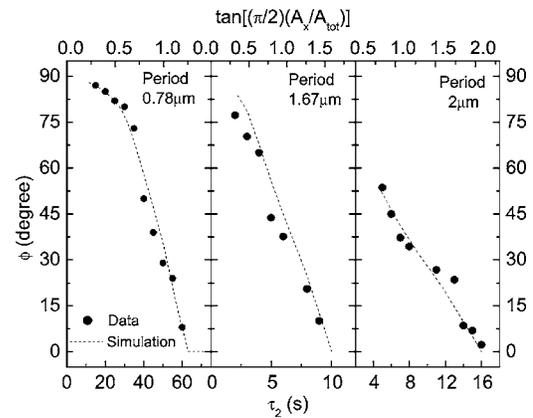


FIG. 3.  $\phi$  vs  $\tau_2$  for the  $p=2$ , 1.6, and 0.78  $\mu\text{m}$  patterns (solid circles, lower axis). The dashed lines are simulations of  $\phi$  plotted against  $\tan(\pi A_x/2A_{\text{tot}})$  (upper axis).

According to the diffusion model,<sup>24</sup> for azodye films with preexisting alignment, interactions among the azodye molecules cause an additional term,  $a\langle P_2(\theta) \rangle P_2(\theta - \theta_0)$ , to the effective potential governing the azodye alignment (where  $a$  is a constant and  $\theta_0$  is the direction of the existing alignment). For  $\theta_0 = 90^\circ$ , i.e., the preexisting alignment is  $\perp \mathbf{P}$ , the incident UV must possess an intensity larger than a threshold  $\propto 3a\langle P_2(\theta) \rangle/k_B T$  before the original azodye alignment can be altered.

We examine the validity of this prediction. The SD-1 film is exposed to uniform UV irradiation twice with the same sequence of polarization as before. The first and second exposure times are fixed at 24 and 6 s, respectively. The second exposure intensity  $I_2$  is kept at 2.82  $\text{mW}/\text{cm}^2$  and the first exposure intensity  $I_1$  varied. The result, plotted as  $\phi$  vs  $I_1$ , is displayed in Fig. 4 by the solid squares. As seen, the second exposure begins to overwrite the alignment effect of the first exposure when  $I_1$  falls below 2.2  $\text{mW}/\text{cm}^2$ . But a similar experiment with  $I_2$  increased to 6.18  $\text{mW}/\text{cm}^2$  (open circles) shows that overwriting occurs even for much larger  $I_1$ .

This result implies that the ultimate growth of the  $x$  alignment domains shown in Fig. 3 cannot occur by a simple rotation of the azodye molecules from  $y$  to  $x$  energized by the second exposure. We propose that it occurs by a systematic progression of the domain walls where  $\langle P_2(\theta) \rangle = 0$  so that no threshold intensity is required for overwriting. Consider the conservation of energy when a domain wall moves to expand the  $x$  domains at the expense of the  $y$  domains,

TABLE I. UV exposure conditions and azimuthal surface energies.

Period ( $\mu\text{m}$ )	First UV exposure ( $\downarrow$ )		Second UV exposure ( $\leftrightarrow$ )		Azimuthal surface energy ( $10^{-5} \text{ J}/\text{m}^2$ )	
	Average UV intensity ( $\text{mW}/\text{cm}^2$ )	$\tau_1$ (s)	Average UV intensity ( $\text{mW}/\text{cm}^2$ )	$\tau_2$ (s)	Inhomogeneous alignment ( $W_{\phi, \text{eff}}$ )	Uniform alignment ( $W_\phi$ )
2	1.94	24	2.95	6	0.25 $\pm$ 0.05	1.95 $\pm$ 0.4
1.67	2.02	16	2.99	5	0.15 $\pm$ 0.05	1.64 $\pm$ 0.4
0.78	0.45	110	0.46	43	0.08 $\pm$ 0.05	1.43 $\pm$ 0.4

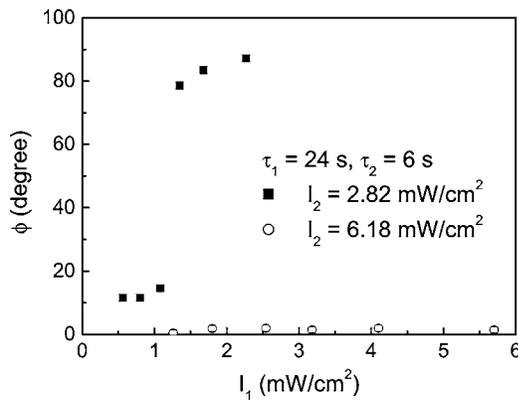


FIG. 4. Average LC azimuthal alignment found on SD-1 films exposed to a uniform UV laser beam polarized along  $x$  for 24 s with different intensities  $I_1$  (plotted as the abscissa) followed by a second uniform exposure with UV polarization changed to  $y$  for 6 s and a fixed intensity of  $I_2$ , set to 2.82 and 6.18  $\text{mW}/\text{cm}^2$  for the two measurement series shown.

$$(\chi_{\parallel} - \chi_{\perp}) \frac{E(x)^2}{2} \frac{d|x|}{dt} h w = - \frac{dU(\theta)}{d\theta} \frac{d\theta}{dt}, \quad (1)$$

where  $\chi_{\parallel}$  and  $\chi_{\perp}$  are the electric susceptibilities of the SD-1 layer  $\parallel$  and  $\perp$ , respectively, to the electric field  $E(x)$  of the UV light,  $x$  is the coordinate of the domain wall,  $t$  is the time,  $h$  and  $w$  are, respectively, the thickness and width (along  $y$ ) of the SD-1 layer, and  $U(\theta) = (1/2)I_2(x)ahw\tau \cos^2 \theta$  is the potential energy governing the azodye alignment.<sup>24</sup> [Here,  $\alpha$  ( $\text{cm}^{-1}$ ) is the absorption coefficient of the SD-1 layer and  $\tau$  is the relaxation time for the rotation of the azodye molecules.] The absolute sign in Eq. (1) ensures that the  $x$  domains always expand at the expense of the  $y$  domains to lower the energy. By adopting  $E(x)^2 \propto I_2(x)$  and  $d\theta/dt \propto I_2(x)$ ,<sup>24</sup> Eq. (1) leads to  $d|x|/dt \propto I_2(x) \propto \cos^2(\pi x/p)$ . Integrating once gives  $\pi|x|/p \propto \tan^{-1} t$ . Since the  $x$  domains expand through simultaneous advancement of the left and right walls,  $A_x/A_{\text{tot}} = 2|x|/p$  and  $t \propto \tan(\pi A_x/2A_{\text{tot}})$ .

We simulate the variation of  $\phi$  with  $\tan(\pi A_x/2A_{\text{tot}})$  by using the model of Ref. 15 and assuming the values of  $W_{\phi}$  in Table I. The results are displayed by dashed lines in Fig. 3. Clearly, the simulations provide a good description of the data. The model also implies that the time scale for complete overwrite of the first alignment effect varies linearly with  $p$  and  $(d\theta/dt)^{-1} (\propto I_2^{-1})$  from above). From Table I, the ratio  $p/I_2$  for  $p=2: 1.67: 0.78 \mu\text{m}$  patterns is 0.40: 0.33: 1, which agrees reasonably well with the ratio for the observed  $\tau_2$  for complete overwrite, i.e., 0.27: 0.15: 1 (Fig. 3). The system-

atically shorter measured time than predicted may come from the assumption that  $d\theta/dt \propto I_2(x)$ , which is due to calculations assuming the incident UV to be uniform.<sup>24</sup> This overlooks torques that can arise from elastic recoil from the inhomogeneous azodye field and cause the discrepancy.

The authors are grateful to Professor W. Y. Tam for assistance in building the optical setup and Professor C. T. Chan for permission to use his He-Cd laser. This work is supported by the Research Grant Council of Hong Kong through Project No. HKUST6115/03E.

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